



SLOVENSKI STANDARD
SIST EN IEC 61000-4-6:2023

01-september-2023

**Elektromagnetna združljivost (EMC) - 4-6. del: Preskusne in merilne tehnike -
Odpornost proti motnjam po vodnikih, ki jih inducirajo radiofrekvenčna polja**

Electromagnetic compatibility (EMC) - Part 4-6: Testing and measurement techniques -
Immunity to conducted disturbances, induced by radio-frequency fields

Elektromagnetische Verträglichkeit (EMV) - Teil 4-6: Prüf- und Messverfahren -
Störfestigkeit gegen leitungsgeführte Störgrößen, induziert durch hochfrequente Felder

Compatibilité électromagnétique (CEM) - Partie 4-6: Techniques d'essai et de mesure -
Immunité aux perturbations conduites, induites par les champs aux fréquences
radioélectriques

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**Electromagnetic compatibility (EMC) - Part 4-6: Testing and measurement techniques - Immunity to conducted disturbances, induced by radio-frequency fields
(IEC 61000-4-6:2023)**

Compatibilité électromagnétique (CEM) - Partie 4-6:
Techniques d'essai et de mesure - Immunité aux perturbations conduites, induites par les champs aux fréquences radioélectriques
(IEC 61000-4-6:2023)

Elektromagnetische Verträglichkeit (EMV) - Teil 4-6: Prüf- und Messverfahren - Störfestigkeit gegen leitungsgeführte Störgrößen, induziert durch hochfrequente Felder
(IEC 61000-4-6:2023)

This European Standard was approved by CENELEC on 2023-07-11. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the CEN-CENELEC Management Centre or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the CEN-CENELEC Management Centre has the same status as the official versions.

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Rue de la Science 23, B-1040 Brussels

EN IEC 61000-4-6:2023 (E)**European foreword**

The text of document 77B/863/FDIS, future edition 5 of IEC 61000-4-6, prepared by SC 77B "High frequency phenomena" of IEC/TC 77 "Electromagnetic compatibility" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 61000-4-6:2023.

The following dates are fixed:

- latest date by which the document has to be implemented at national (dop) 2024-04-11 level by publication of an identical national standard or by endorsement
- latest date by which the national standards conflicting with the (dow) 2026-07-11 document have to be withdrawn

This document supersedes EN 61000-4-6:2014 and all of its amendments and corrigenda (if any).

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. CENELEC shall not be held responsible for identifying any or all such patent rights.

This document has been prepared under a standardization request addressed to CENELEC by the European Commission. The Standing Committee of the EFTA States subsequently approves these requests for its Member States.

Any feedback and questions on this document should be directed to the users' national committee. A complete listing of these bodies can be found on the CENELEC website.

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The text of the International Standard IEC 61000-4-6:2023 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standard indicated:

IEC 61000-4-3 NOTE Approved as EN IEC 61000-4-3

CISPR 16-1-4 NOTE Approved as EN IEC 55016-1-4

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
CISPR 16-1-2	-	Specification for radio disturbance and immunity measuring apparatus and methods - Part 1-2: Radio disturbance and immunity measuring apparatus - Coupling devices for conducted disturbance measurements	EN 55016-1-2	-

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INTERNATIONAL STANDARD



BASIC EMC PUBLICATION

**Electromagnetic compatibility (EMC) –
Part 4-6: Testing and measurement techniques – Immunity to conducted
disturbances, induced by radio-frequency fields**

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

ELECTROMAGNETIC COMPATIBILITY (EMC) –**Part 4-6: Testing and measurement techniques –
Immunity to conducted disturbances, induced by radio-frequency fields**

FOREWORD

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
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IEC 61000-4-6 has been prepared by subcommittee 77B: High frequency phenomena, of IEC technical committee 77: Electromagnetic compatibility. It is an International Standard.

It forms Part 4-6 of IEC 61000. It has the status of a basic EMC publication in accordance with IEC Guide 107.

This fifth edition cancels and replaces the fourth edition published in 2013. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) selection of injection devices revised;
- b) need of AE impedance check for clamp injection removed and Annex H deleted;
- c) saturation check revised;
- d) new Annex H on testing with multiple signals;

e) level-setting only with feedback loop.

The text of this International Standard is based on the following documents:

Draft	Report on voting
77B/863/FDIS	77B/865/RVD

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/publications.

A list of all parts in the IEC 61000 series, published under the general title *Electromagnetic compatibility (EMC)*, can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under webstore.iec.ch in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

<https://standards.iteh.ai/catalog/standards/sist/084b05fd-ebe6-46ef-b009-b423209b7feb/sist-en-iec-61000-4-6-2023>

IMPORTANT – The "colour inside" logo on the cover page of this document indicates that it contains colours which are considered to be useful for the correct understanding of its contents. Users should therefore print this document using a colour printer.

INTRODUCTION

IEC 61000 is published in separate parts according to the following structure:

Part 1: General

General considerations (introduction, fundamental principles)

Definitions, terminology

Part 2: Environment

Description of the environment

Classification of the environment

Compatibility levels

Part 3: Limits

Emission limits

Immunity limits (in so far as they do not fall under the responsibility of the product committees)

Part 4: Testing and measurement techniques

Measurement techniques

Testing techniques

Part 5: Installation and mitigation guidelines

Installation guidelines

Mitigation methods and devices

Part 6: Generic standards

Part 9: Miscellaneous

Each part is further subdivided into several parts, published either as international standards or as technical specifications or technical reports, some of which have already been published as sections. Others will be published with the part number followed by a dash and a second number identifying the subdivision (example: IEC 61000-6-1).

This part is an international standard which gives immunity requirements and test procedures related to conducted disturbances induced by radio-frequency fields.

ELECTROMAGNETIC COMPATIBILITY (EMC) –

Part 4-6: Testing and measurement techniques – Immunity to conducted disturbances, induced by radio-frequency fields

1 Scope

This part of IEC 61000 relates to the conducted immunity requirements of electrical and electronic equipment to electromagnetic disturbances coming from intended radio-frequency (RF) transmitters in the frequency range 150 kHz up to 80 MHz.

NOTE 1 Product committees might decide to use the methods described in this document also for frequencies up to 230 MHz (see Annex B) although the methods and test instrumentation are intended to be used in the frequency range up to 80 MHz.

Equipment not having at least one conducting wire or cable (such as mains supply, signal line or earth connection) which can couple the equipment to the disturbing RF fields is excluded from the scope of this document.

NOTE 2 Test methods are specified in this part of IEC 61000 to assess the effect that conducted disturbing signals, induced by electromagnetic radiation, have on the equipment concerned. The simulation and measurement of these conducted disturbances are not adequately exact for the quantitative determination of effects. The test methods specified are structured for the primary objective of establishing adequate repeatability of results at various facilities for quantitative analysis of effects.

The object of this document is to establish a common reference for evaluating the functional immunity of electrical and electronic equipment when subjected to conducted disturbances induced by RF fields. The test method in this document describes a consistent method to assess the immunity of an equipment or system against a specified phenomenon.

NOTE 3 As described in IEC Guide 107, this document is a basic EMC publication for use by product committees of the IEC. As also stated in Guide 107, the IEC product committees are responsible for determining whether this immunity test standard should be applied or not, and if applied, they are responsible for determining the appropriate test levels and performance criteria.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

CISPR 16-1-2, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 1-2: Radio disturbance and immunity measuring apparatus – Coupling devices for conducted disturbance measurements*

3 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

ISO and IEC maintain terminology databases for use in standardization at the following addresses:

- IEC Electropedia: available at <https://www.electropedia.org/>
- ISO Online browsing platform: available at <https://www.iso.org/obp>